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BYD Microelectronics Co., Ltd.

# BG200B12LY

## IGBT Power Module

$V_{CE} = 1200V$      $I_C = 200A$

### General Description

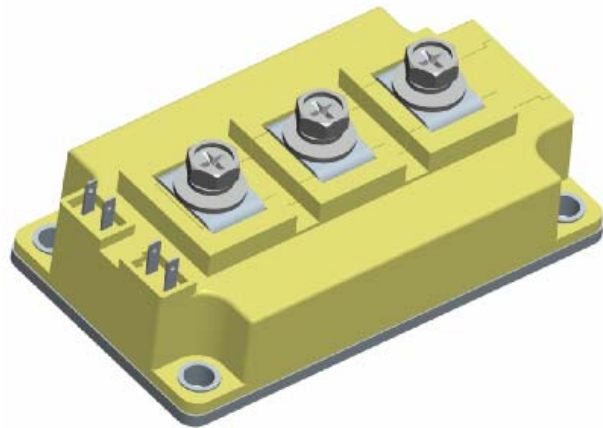
BYD IGBT Power Module BG200B12LY provides ultra low conduction loss as well as high short circuit capability, which introduce the advanced IGBT chip/FWD and improved connection, it is able to take on a perfect performance in various applications under 25KHz.

### Features

- Half-bridge
- Low inductance
- Standard package
- High short circuit capability
- Ultra low conduction and switching loss
- Including fast&soft recovery anti-parallel FWD

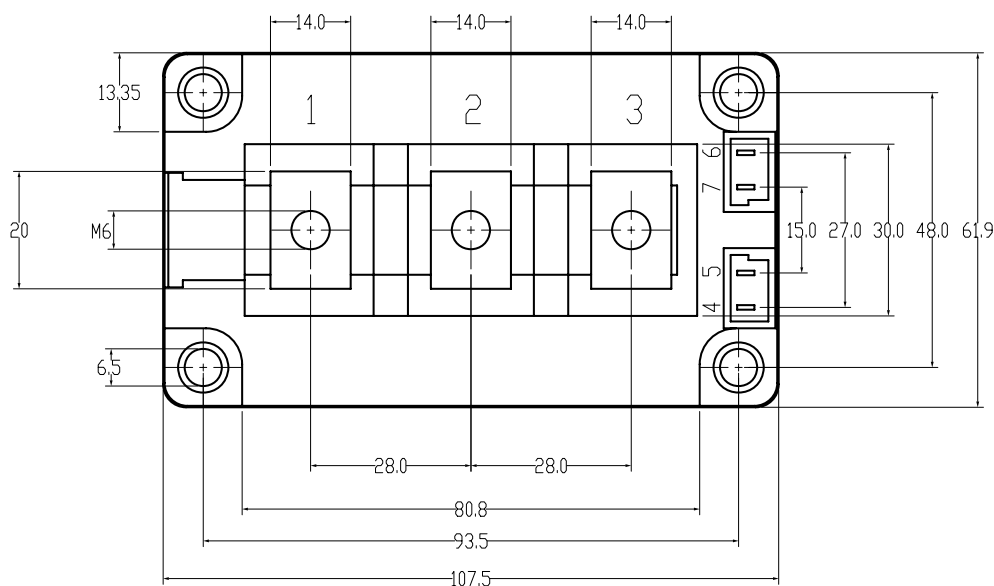
### Applications

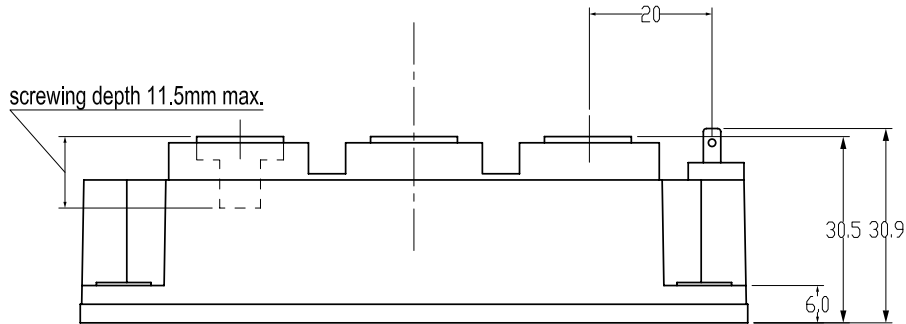
- AC motor control
- Inverters
- Servo
- UPS (Uninterruptible Power Supplies)
- Electronic welding



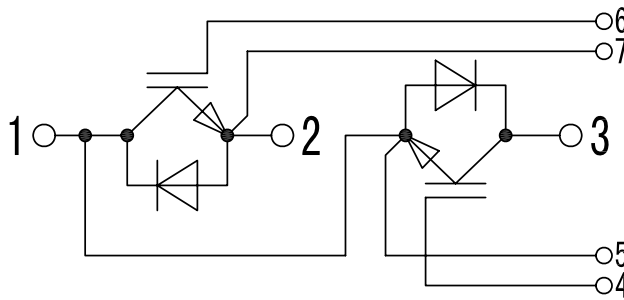
### Package Outlines

Dimensions in mm





### Circuit Diagram



### Characteristic values

Parameter	Symbol	Conditions	Temp	Value		Unit
<b>Absolute Maximum Ratings</b>						
				min	max	
Collector-emitter voltage	$V_{CES}$	$V_{GE}=0V$	$T_{vj}=25^{\circ}C$	—	1200	V
Continuous collector current	$I_c$	—	$T_{vj}=80^{\circ}C$	—	200	A
Peak collector current	$I_{CM}$	$t=1ms$	$T_{vj}=80^{\circ}C$	—	400	A
Gate-emitter voltage	$V_{GES}$	—	—	-20	20	V
IGBT short circuit SOA	$t_{psc}$	$V_{CC}=900V, V_{CEM} \leq 1200V, V_{GE} \leq 15V$	$T_{vj} \leq 125^{\circ}C$	—	10	$\mu s$
Virtual junction temperature	$T_{vj}$	—	—	-40	150	$^{\circ}C$
Storage temperature range	$T_{stg}$	—	—	-40	125	$^{\circ}C$
Repetitive peak reverse voltage	$V_{RRM}$	—	—	—	1200	V
forward current	$I_F$	—	—	—	200	A
Isolation test voltage	$V_{isol}$	$1min, f=50Hz$	—	—	2500	V



Characteristics							
IGBT				min	typ	max	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_c=4mA, V_{CE}=V_{GE}$	—	5	6.2	7	V
Collector-emitter cut-off current	$I_{CES}$	$V_{CE}=1200V, V_{GE}=0V$	$T_{vj}=25^{\circ}C$	—	—	0.1	mA
			$T_{vj}=125^{\circ}C$	—	0.4	—	mA
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_c=100A, V_{GE}=15V$	$T_{vj}=25^{\circ}C$	—	1.8	—	V
			$T_{vj}=125^{\circ}C$	—	2	—	V
Input capacitance	$C_{ies}$	$V_{CE}=25V, V_{GE}=0V, f=1MHz$	$T_{vj}=25^{\circ}C$	—	7.43	—	nF
Output capacitance	$C_{oes}$			—	0.52	—	nF
Reverse transfer capacitance	$C_{res}$			—	0.34	—	nF
Turn-on delay time	$t_{d(on)}$	$V_{CC}=600V, I_c=100A, R_g=6.8\Omega, V_{GE}=\pm 15V, L=60nH, \text{inductive load}$	$T_{vj}=25^{\circ}C$	—	125	—	ns
			$T_{vj}=125^{\circ}C$	—	135	—	ns
Rise time	$t_r$		$T_{vj}=25^{\circ}C$	—	60	—	ns
			$T_{vj}=125^{\circ}C$	—	60	—	ns
Turn-off delay time	$t_{d(off)}$		$T_{vj}=25^{\circ}C$	—	420	—	ns
			$T_{vj}=125^{\circ}C$	—	490	—	ns
Fall time	$t_f$		$T_{vj}=25^{\circ}C$	—	60	—	ns
			$T_{vj}=125^{\circ}C$	—	75	—	ns
Energy dissipation during turn-on time	$E_{on}$	$V_{CC}=600V, I_c=100A, R_g=6.8\Omega, V_{GE}=\pm 15V, L=60nH, \text{inductive load}$	$T_{vj}=25^{\circ}C$	—	8.6	—	mJ
			$T_{vj}=125^{\circ}C$	—	12.4	—	mJ
Energy dissipation during turn-off time	$E_{off}$	$V_{CC}=600V, I_c=100A, R_g=6.8\Omega, V_{GE}=\pm 15V, L=60nH, \text{inductive load}$	$T_{vj}=25^{\circ}C$	—	6.8	—	mJ
			$T_{vj}=125^{\circ}C$	—	10.8	—	mJ
Diode				min	typ	max	
Continuous forward voltage	$V_F$	$I_F=100A$	$T_{vj}=25^{\circ}C$	—	—	1.85	V
			$T_{vj}=150^{\circ}C$	—	—	1.9	V
Peak reverse recovery current	$I_{RM}$	$I_F=100A, V_{CC}=600V, di/dt=1800A/\mu s, L=60nH, \text{inductive load}$	$T_{vj}=125^{\circ}C$	—	115	—	A
Recovered charge	$Q_{rr}$		$T_{vj}=125^{\circ}C$	—	27.2	—	$\mu C$
Reverse recovery time	$t_{rr}$		$T_{vj}=125^{\circ}C$	—	180	—	ns
Reverse recovery energy	$E_{rec}$		$T_{vj}=125^{\circ}C$	—	11.5	—	mJ

Thermal-Mechanical Specifications							
Parameter	Symbol	Conditions	min	typ	max	Unit	
IGBT thermal resistance junction to case	$R_{th(j-c)}$	per switch	—	—	0.064	K/W	
Diode thermal resistance junction to case	$R_{th(j-c)}$		—	—	0.144	K/W	
IGBT thermal resistance case to heat-sink	$R_{th(c-s)}$	IGBT per switch, I grease = 1W/m x K	—	0.024	—	K/W	
Diode thermal resistance case to heat-sink	$R_{th(c-s)}$	Diode per switch, I grease = 1W/m x K	—	0.048	—	K/W	
Dimensions	L x W x H	Typical , see outline drawing	107.5 x 61.9 x 30.9			mm	
Clearance distance in air	da	according to IEC 60664-1 and EN 50124-1	Term. to base:	—	—	28.3	mm
			Term. to term:	6	—	—	
Surface creepage distance	ds	according to IEC 60664-1 and EN 50124-1	Term. to base:	—	24	—	mm
			Term. to term:	—	14	—	
Mass	m	—	—	342	—	gr	

Thermal and mechanical properties according to IEC 60747 – 15

### Characterization curves

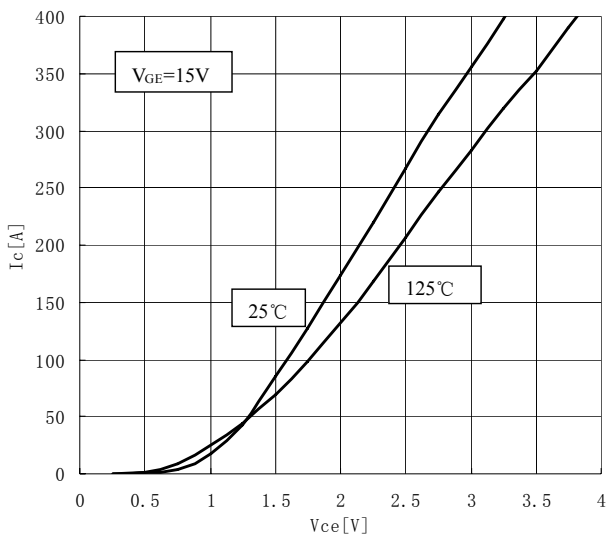


Fig.1 Typical Output Characteristics

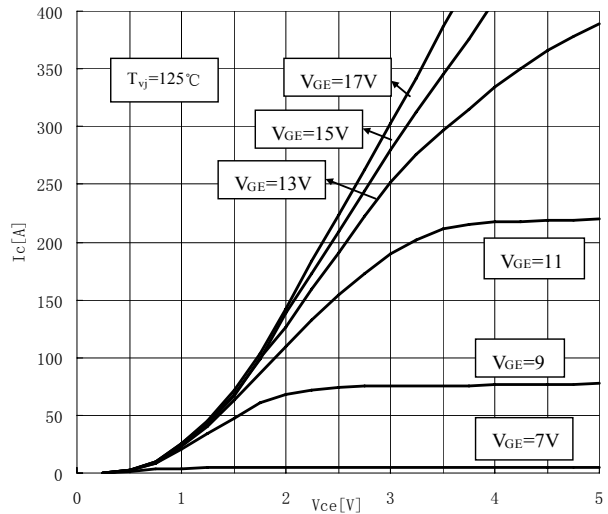


Fig.2 Typical Output Characteristics

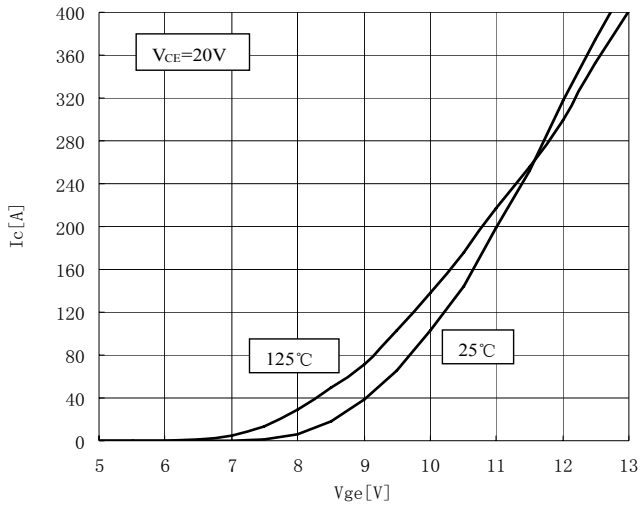


Fig.3 Typical Transfer Characteristics

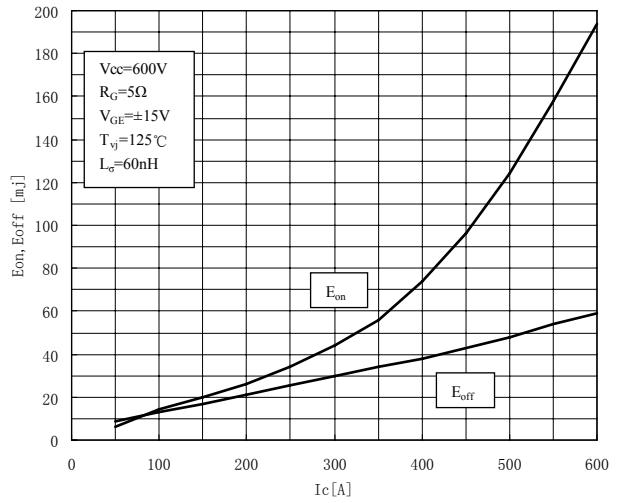


Fig.4 Switching Loss vs. Collector current

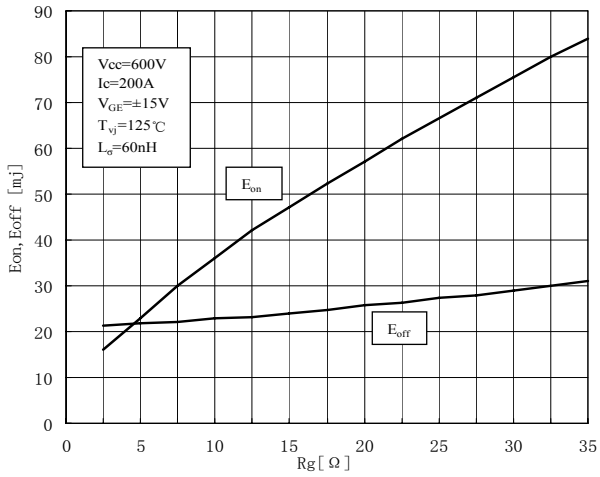


Fig.5 Switching Loss vs. Gate Resistor

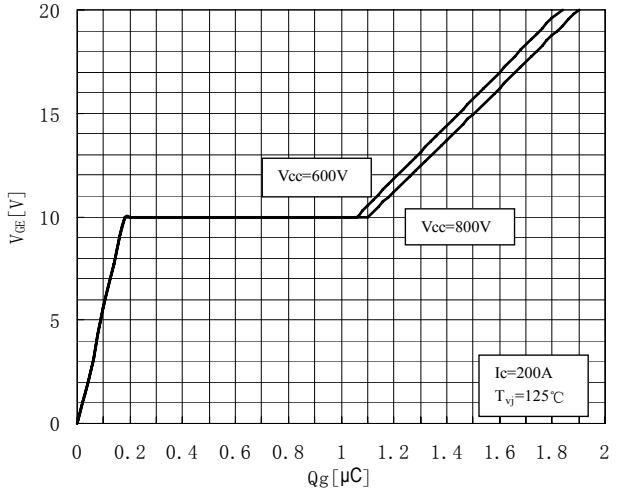


Fig.6 Typical Gate Charge Characteristics

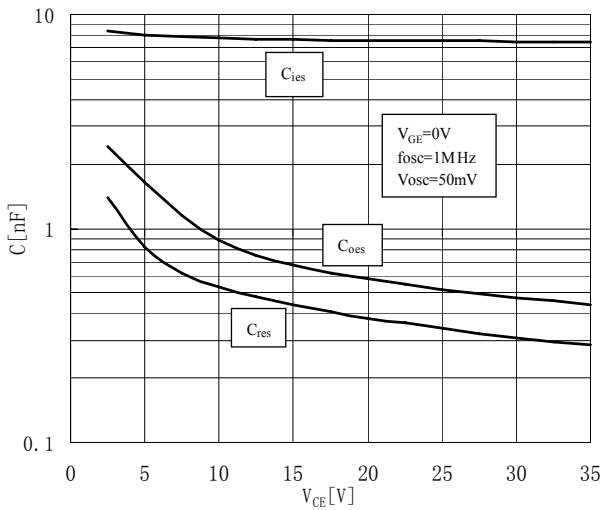


Fig.7 Typical Capacitances vs Collector-Emitter Voltage ( chip level )



## Attention

- 1、 In order to reduce the contact resistance, we suggest add thermal grease between base and heat-sink, which thickness is about 0.1mm.
- 2、 When installing the module, please wear a electrostatic bracelet to prevent the gate breakdown and the imbalance power may damage the internal chip, even to damage the module.
- 3、 This is an electrostatic sensitive device, please observe the international standard IEC 60747-1, chap. IX.

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